




# Saturable absorption properties and femtosecond mode-locking application of titanium trisulfide

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## ABSTRACT

Titanium trisulfide (TiS<sub>3</sub>) is regarded as a candidate material for optoelectronic devices and nano-transistors due to its photoresponse. However, its nonlinear optical response in a mode-locked laser is yet to be investigated. Here, the performance of TiS<sub>3</sub> as a saturable absorber in a mode-locked laser is demonstrated. The generated mode-locked pulses achieve pulse duration as short as 147.72 fs at 1555 nm, which indicates that TiS<sub>3</sub> as a potential functional material has applications in nanomaterial-related photonics.

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It is generally considered that the discovery of graphene lays a foundation for the research of two-dimensional (2D) materials.<sup>1,2</sup> From then on, some kinds of 2D materials have begun to rise and have become research hotspots in the fields of photonics and optoelectronics.<sup>3–5</sup> There is still a long way to go for 2D materials as mature integrated circuit devices in terms of manufacturing technology, cost, reliability, and performance. However, as single independent devices, 2D materials have prominent performance in optical modulation and optical detection.<sup>6–8</sup> The miniaturization of 2D materials makes them more flexible for applications, and their optical and photoelectric properties such as high nonlinearity and ultrafast carrier dynamics improve the performance of optoelectronic devices.<sup>9,10</sup>

At present, some 2D materials, such as graphene,<sup>11–13</sup> transition metal dichalcogenides (TMDs),<sup>14–17</sup> topological insulators<sup>18–21</sup> and black phosphorus,<sup>22–25</sup> have achieved remarkable performance in the application of optical modulation devices. In particular, TMDs, as a large family that includes more than 40 different materials uniformly expressed as MX<sub>2</sub> (M: Mo, W, etc; X: S, Se, etc.), have been explored.<sup>26</sup> In TMDs, the adjacent individual layers bond together by weak van der Waals forces, which is propitious to the exfoliation of monolayer or few-layer forms.<sup>27</sup> Taking MoS<sub>2</sub> as an example, bulk MoS<sub>2</sub> exhibits an indirect bandgap of 1.29 eV, while eventually it shows a direct bandgap of 1.80 eV as the thickness decreases to monolayer.<sup>28</sup> Some

research highlights the photoelectric properties of MoS<sub>2</sub>, including the photoluminescence in MoS<sub>2</sub> layers,<sup>29</sup> the on/off ratio exceeding  $1 \times 10^8$ , a mobility of  $\sim 200 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  in the field-effect transistor,<sup>30</sup> a third-order nonlinear optical susceptibility of  $\sim 10^{-15} \text{ esu}$  higher than that of graphene,<sup>31</sup> and a broadband nonlinear response covering  $1\text{--}2 \mu\text{m}$ .<sup>32</sup>

TiS<sub>3</sub>, as a semiconducting chalcogenide material similar to TMD material MoS<sub>2</sub>, also possesses a thickness-related bandgap structure. The bulk TiS<sub>3</sub> exhibits an indirect bandgap of 0.94 eV, and the monolayer TiS<sub>3</sub> has an indirect bandgap of 1.02 eV.<sup>33</sup> However, TiS<sub>3</sub> shows strong anisotropy due to different crystal symmetries.<sup>34</sup> The optical responses in different polarization directions up to 4:1 originating from in-plane optical selection induced by strong anisotropy have generated widespread interest. What is more, TiS<sub>3</sub> exhibits on/off ratios of up to  $\sim 7000$  and a mobility of  $43 \text{ cm}^2 \text{ V}^{-1} \text{ s}^{-1}$  and can be a candidate material for optoelectronic devices and nanotransistors.<sup>35</sup> In the previous work, the application of TiS<sub>3</sub> in Q-switched lasers has been discussed.<sup>36</sup> However, using TiS<sub>3</sub>, the mode-locked lasers with femtosecond pulses have not been demonstrated. Such femtosecond pulses have advantages in material precision machining, femtosecond time spectroscopy, and nanoimaging. This motivation leads us to explore the performance of TiS<sub>3</sub> in the mode-locked lasers with femtosecond pulses.

Here, the generation of femtosecond pulses from the mode-locked fiber lasers based on the  $\text{TiS}_3$  saturable absorber (SA) is reported.  $\text{TiS}_3$  SA is fabricated by chemical vapor transport (CVT) technology and shows optical nonlinearity at 1555 nm. After the employment of the  $\text{TiS}_3$  SA in the fiber laser, the stable mode-locked operation at 1555 nm is demonstrated. The pulse duration of the mode-locked laser is as short as 147.72 fs. The good performance of lasers enables us to emphasize the applicability of  $\text{TiS}_3$  as a feasible SA candidate in mode-locked lasers and explore more photonic applications.

$\text{TiS}_3$  here was prepared by CVT technology, in which the metastable phase single crystal is able to be obtained by temperature gradient transmission. After material preparation, the subsequent transfer process was performed. Detailed transfer processes have been illustrated in a previous report.<sup>37</sup> The atomic force microscopy (AFM) image in Fig. 1(a) shows the surface topography of the  $\text{TiS}_3$  nanosheet. By comparing the difference in thickness between the reference plane and the top surface of  $\text{TiS}_3$  in Fig. 1(a), the thickness of the  $\text{TiS}_3$  film was  $\sim 182$  nm. Because the  $\text{TiS}_3$  material produced by the CVT technology in our experiments was needle-shaped, it was difficult to reconcile the demands of large size and few layers. Although it falls outside the scope of our ability at present due to the crystal size produced by our growth process, it is attractive to investigate the thickness-related saturable absorption of  $\text{TiS}_3$  in the future.

Although the thickness of  $\text{TiS}_3$  was 182 nm, it is different from the general bulk  $\text{TiS}_3$ . On the one hand,  $\text{TiS}_3$  was obtained by further using the mechanical exfoliation method after the CVT method, which indicates that the dimensionality of  $\text{TiS}_3$  is further reduced in the

preparation process. On the other hand,  $\text{TiS}_3$  with a thickness of 182 nm showed the same properties in the Raman spectrum as the layered  $\text{TiS}_3$  as shown in Fig. 1(b), which is consistent with a previous report.<sup>38</sup> The two peaks representing the interior vibration of  $\text{TiS}_3$  were located at 300 (II:  $A_g^{\text{internal}}$ ) and 371  $\text{cm}^{-1}$  (III:  $A_g^{\text{internal}}$ ). The peak at 558  $\text{cm}^{-1}$  showed the vibration characteristics of S-S pairs. The peak displayed at 522  $\text{cm}^{-1}$  was mainly Si derived from the substrate.<sup>39</sup> Ignoring the influence of the base element, it is known from the vibration mode peaks belonging to  $\text{TiS}_3$  in the Raman spectrum that  $\text{TiS}_3$  was prepared.

Figure 1(c) shows the absorption characteristics of  $\text{TiS}_3$  in the near-infrared range. It is worth noting that  $\text{TiS}_3$  exhibited 32% transmittance at 1550 nm. A Tauc plot from the data in Fig. 1(c) is shown in Fig. 1(d), which indicates that the bandgap of  $\text{TiS}_3$  was estimated to be 0.58 eV. The range of wavelengths incident on  $\text{TiS}_3$  was from 950 to 1800 nm. The experimental value of 0.58 eV was different from the theoretical value of 1.05 eV. According to previous studies, the reduction of the bandgap may be caused by the defect state.<sup>40</sup> This defect states in  $\text{TiS}_3$  are likely to be introduced through the production process. Yu *et al.* demonstrated that the  $\text{MoS}_2$  bandgap can be reduced from 1.08 to 0.08 eV by introducing the defects in a suitable range.<sup>41</sup> This reduction in bandgap is believed by some researchers to be a plausible cause for subband absorption. Therefore, it can be concluded that the decrease in the bandgap of  $\text{TiS}_3$  is caused by some defects, which results in the absorption of  $\text{TiS}_3$  at 1550 nm. The carrier dynamic relaxation process of  $\text{TiS}_3$  is shown in Fig. 1(e). In the pump-probe measurement, the 500 nm pump beam has a pulse energy of 2.2  $\mu\text{J}$  and a diameter of 250  $\mu\text{m}$ . The 800 nm pulse with a diameter of 120  $\mu\text{m}$  was used to generate a white light continuum probe beam. After theoretical fitting, the relaxation time was as short as 1.34 ps, which indicates the potential applications of  $\text{TiS}_3$  in ultrafast photonics. The optical nonlinearity of the  $\text{TiS}_3$  SA, which is represented by power-dependent transmission characteristics, was measured by a balanced twin-detector method. The detailed process has been introduced in a previous report.<sup>42</sup> The results and fitting curve are shown in Fig. 1(f). The unsaturated loss as low as  $\sim 6\%$  indicated the small insertion loss of the  $\text{TiS}_3$  SA. The modulation depth was up to 39.39%, which aroused our curiosity about its performance in lasers. The light source of measurement was a home-made mode-locked laser operating at 1550 nm with a pulse duration of 700 fs.

As shown in Fig. 2(a), the Er-doped fiber laser (EDFL) that was constructed from single-mode fiber-integrated components was established. Optical devices including an isolator (ISO) that keeps light unidirectional propagating, a 20:80 output coupler (OC) for spectral and temporal monitoring, a segment of 0.6 m EDF (Liekki 110-4/125) used to enhance light intensity, and a polarization controller (PC) that is capable of fine tuning the polarization state and net cavity birefringence were all integrated into a typical ring cavity. The assembled

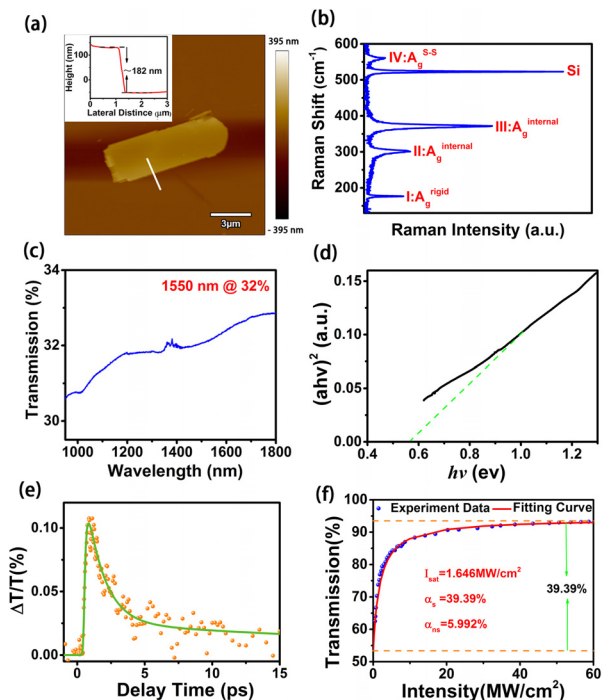


FIG. 1. (a) AFM micrograph, (b) Raman spectrum, (c) absorption spectrum, (d) Tauc plot, (e) transmittivity transients, and (f) absorption characteristics of  $\text{TiS}_3$ .

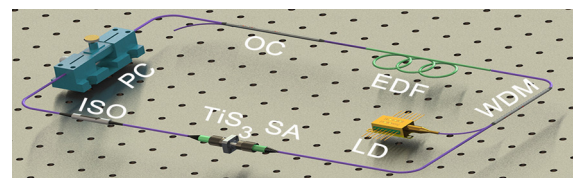


FIG. 2. EDFL based on the  $\text{TiS}_3$  SA.

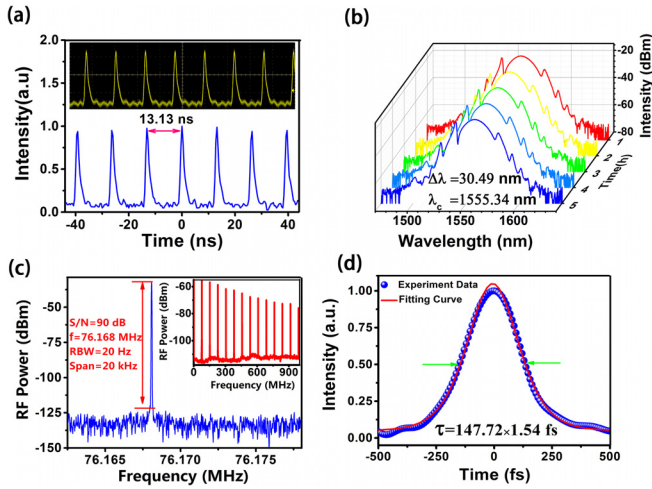


FIG. 3. Performance of EDFL based on the TiS<sub>3</sub> SA: (a) pulse train, (b) spectrum, (c) RF spectrum, and (d) pulse duration.

system was pumped by a commercial 980 nm laser diode (LD) through a 980/1550 nm wavelength division multiplexor (WDM). Prepared TiS<sub>3</sub> SA was placed after ISO for the verification experiment of optical nonlinearity.

Stable mode-locked pulse trains were observed using a real-time monitoring oscilloscope by properly adjusting PC at a pump power of 210 mW. During the sustained pump growth, the mode-locked state remained stable. The waveforms observed on an oscilloscope are collected in Fig. 3 when the pump power increased to a limited power of 630 mW. The mode-locked pulse train showed a uniform time interval of 13.13 ns in Fig. 3(a), and the repetition frequency corresponding to this time interval was in agreement with the experimental data of 76.168 MHz. It was observed from the spectrum that the center wavelength of the system located at 1555.34 nm with a wide 3-dB bandwidth of 30.49 nm in Fig. 3(b). The radio frequency (RF) spectrum with a resolution bandwidth of 20 Hz and a span of 20 kHz, which is considered to be able to reflect the stability of the system, is shown in Fig. 3(c). The signal-to-noise ratio (SNR) of fundamental frequency was up to 90 dB, which indicates that the fluctuation of amplitude is low. Moreover, from the wide monitoring span up to 1 GHz, no

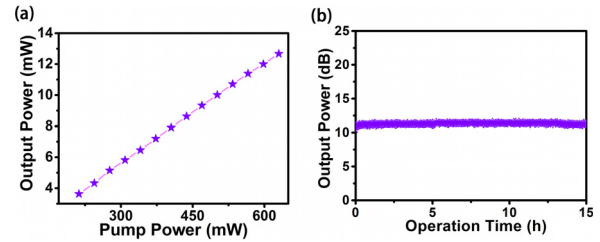


FIG. 4. (a) Trend of output power of the EDFL change with different pump powers. (b) Output power monitoring within 15 h.

noticeable sign was observed from cavity harmonics in the inset of Fig. 3(c), which implies the stability of the system. The actual pulse shape was determined using an autocorrelator. By the sech<sup>2</sup> fitting for pulse in Fig. 3(d), the pulse duration of mode-locked pulses was revealed to be as short as 147.72 fs. According to the information of the spectrum and pulse duration, the time bandwidth product of the mode-locked system was calculated to be 0.5582. It was confirmed that the saturable absorption characteristics came from the TiS<sub>3</sub> SA. When the TiS<sub>3</sub> SA was replaced by the single mode fiber with the same length or fiber ferrules without TiS<sub>3</sub>, the mode-locked pulses cannot be obtained, which indicates that the nonlinearity of the TiS<sub>3</sub> SA was the main reason for realizing the mode-locking of the fiber laser. Figure 4(a) shows the trend of output power of EDFL changing with pump power. The mode-locking threshold of EDFL was 210 mW. The maximum output power of EDFL was 12.67 mW. As the pump power increased, the rate of increase in output power was almost constant. There was no power stagnation or sudden change due to partial damage, which indicates that this SA works normally at higher power. When the incident power remained at the maximum of 630 mW, the output performance of the laser was monitored for a long time as shown in Fig. 4(b). It was observed that the output power of EDFL within 15 h was almost in a straight line, and there was no obvious power jump. The standard deviation of the power obtained by taking the dots at one second intervals within 15 h was 0.193 mW, and the corresponding dispersion was 1.7%, which indicates that the laser is stable. The efficiency (pump power/output power) of this EDFL is 2%.

In order to further evaluate the performance of the TiS<sub>3</sub> SA intuitively, some types of sulfides are listed for comparison in Table I. From the data summarized above, the TiS<sub>3</sub> SA performed well in

TABLE I. Performance comparison of EDFLs based on some sulfides.

Materials	MD(%)	$\Delta\lambda/\lambda(\text{nm})$	SNR(dB)	$\tau$ (fs)	P(mW)	Efficiency	References
TiS <sub>2</sub>	8.3	4.75/1563.3	60	812	...	...	26
Graphene	11	48/1545	65	88	1.5	1.4%	43
MoS <sub>2</sub>	35.4	2.6/1568.9	62	1280	5.1	3.4%	44
	2.5	12.38/1568	61	637	...	...	45
WS <sub>2</sub>	0.95	2.3/1557	>50	1320	...	...	46
	5.1	14.5/1565.5	~70	21 100	1.8	2.1%	47
ReS <sub>2</sub>	0.12	1.85/1559	<60	1600	0.4	0.95%	48
SnS <sub>2</sub>	4.6	6.09/1562.01	>45	623	1.2	0.59%	49
TiS <sub>3</sub>	39.39	30.49/1555.34	90	147.72	12.67	2%	This work

EDFL due to the optical nonlinearity. In our experiments, the modulation depth of the prepared  $\text{TiS}_3$  SA was up to 39.39%, and the pulse duration realized in the experiment was as short as 147.72 fs, which is consistent with the trend reported in previous reports.<sup>49</sup> According to Ref. 50, the pulse duration decreased with the increase in the modulation depth in theory. Regarding the SNR of 90 dB, our laser possessed better stability than mentioned lasers in Table I. Moreover, the  $\text{TiS}_3$ -based laser remained stable at relatively high power, showing the potential to be designed for high-power applications.

In summary, the  $\text{TiS}_3$  SA with a modulation depth of 39.39% has been fabricated by the CVT technology. After the application of prepared  $\text{TiS}_3$  SA with strong saturable absorption in the fiber laser, the ultrashort pulse as short as 147.72 fs has been obtained. Moreover, compared with similar sulfides, the system has performed well in terms of stability and power durability. The results highlight the development potential of  $\text{TiS}_3$  as a promising functional material in various photon applications, especially the generation of ultrashort pulses.

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